

No.1072D

2SC3153

NPN Triple Diffused Planar Silicon Transistor

Switching Regulator Applications

Features

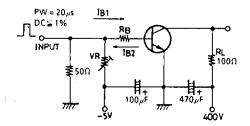
- · High breakdown voltage ($V_{CBO} \ge 900V$).
- · Fast switching time.
- · Wide ASO.

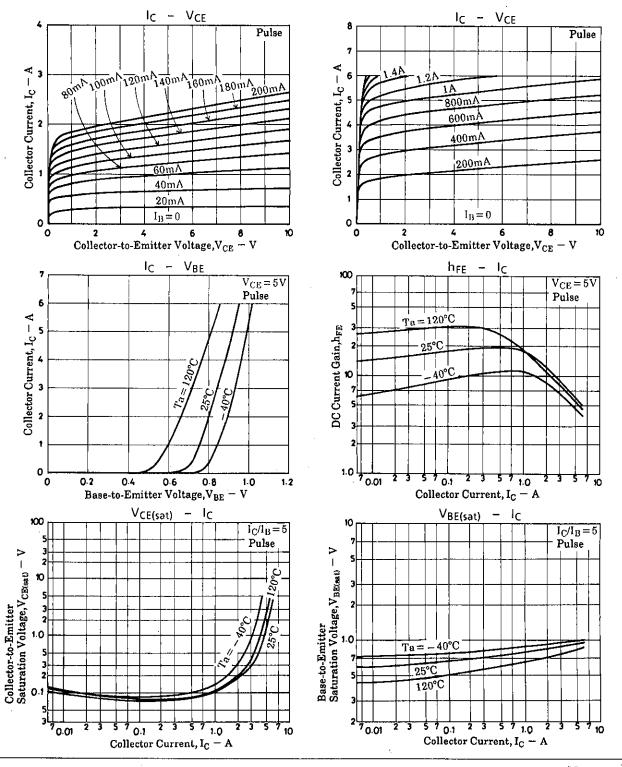
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| Junction Temperature Tj 150 °C |
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| Electrical Characteristics at Ta = 25°C min tyn max uni |
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| DC Current Gain $h_{FE}(1)$ $V_{CE} = 5V$, $I_C = 0.4A$ 10% 40% |
| $h_{FE}(2)$ $V_{CE}=5V, I_{C}=2A$ 8 |
| Gain-Bandwidth Product f_T $V_{CE} = 10V$, $I_C = 0.4A$ 15 MH |
| Output Capacitance Cob $V_{CB}=10V$, $f=1MHz$ 120 pF |
| C-E Saturation Voltage $V_{CE(sat)}$ $I_C=3A$, $I_B=0.6A$ 2.0 V |
| B-E Saturation Voltage $V_{BE(sat)}$ $I_{C}=3A$, $I_{B}=0.6A$ 1.5 V |
| C-B Breakdown Voltage $V_{(BR)CBO}$ $I_C=1mA$, $I_E=0$ 900 V |
| C-E Breakdown Voltage $V_{(BR)CEO}$ $I_C=5mA$, $R_{BE}=\infty$ 800 V |
| E-B Breakdown Voltage $V_{(BR)EBO}$ $I_E=1mA$, $I_C=0$ 7 V |
| C-E Sustain Voltage $V_{CEO(sus)}$ $I_C=6A$, $L=200\mu H$, $I_B=2A$ 800 V |
| $V_{CEX(sus)}(1)$ $I_C=2A$, $I_{B1}=0.4A$, $I_{B2}=-0.4A$, 800 V |
| L=1mH, Clamped |
| $V_{\text{CEX(sus)}}(2) \ I_{\text{C}} = 1A, I_{\text{B1}} = 0.2A, I_{\text{B2}} = -0.2A, 900 $ V |
| L=2mH, Clamped |
| Rise Time t_{on} $I_{C}=4A, I_{B1}=0.8A, I_{B2}=-1.6A,$ 1.0 µs |
| Storage Time t_{stg} $R_L = 100\Omega, V_{CC} = 400V$ 3.0 μs |
| Fall Time t_f 0.7 μs |

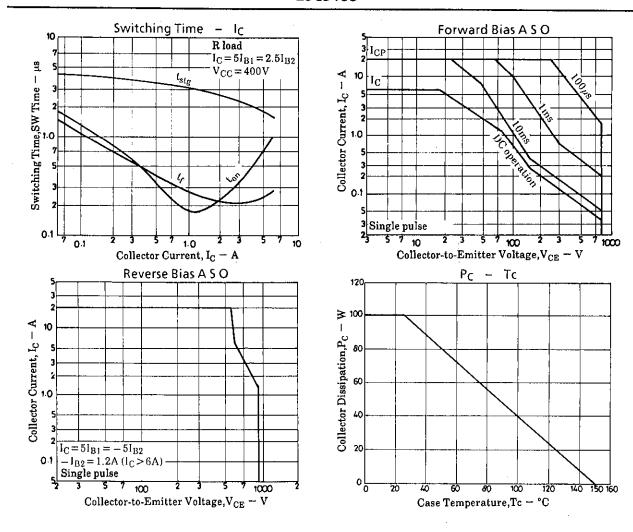
* : For the hFE(1) of the 2SC3153, specify two ranks or more in principle.

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Switching Time Test Circuit







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